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Information technology — Security techniques — Testing methods for the mitigation of non-invasive attack classes against cryptographic modules

Techonologie de l'information — Techniques de sécurité — Methodes de test pour la protection contre les attaques non intrusives des modules cryptographiques

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ISO copyright office
Ch. de Blandonnet 8 • CP 401
CH-1214 Vernier, Geneva, Switzerland
Tel. +41 22 749 01 11
Fax +41 22 749 09 47
copyright@iso.org
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The committee responsible for this document is ISO/IEC JTC 1, *Information technology, SC 27, IT Security techniques*.